BLL6H1214L-250; BLL6H1214LS-250

LDMOS L-band radar power transistor

Rev. 3 — 14 July 2010

Product data sheet

1. Product profile

1.1 General description

250 W LDMOS power transistor intended for L-band radar applications in the 1.2 GHz to 1.4 GHz range.

Table 1. Test information

Typical RF performance at $T_{\rm case}$ = 25 °C; t_p = 300 μ s; δ = 10 %; $I_{\rm Dq}$ = 100 mA; in a class-AB production test circuit.

Mode of operation	f (GHz)	V _{DS}	P _L (W)	G _p	η _D	t _r	t _f
	(GHZ)	(V)	(VV)	(dB)	(%)	(ns)	(ns)
pulsed RF	1.2 to 1.4	50	250	17	55	15	5

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

1.2 Features and benefits

- Typical pulsed RF performance at a frequency of 1.2 GHz to 1.4 GHz, a supply voltage of 50 V, an I_{Dq} of 100 mA, a t_p of 300 μs with δ of 10 %:
 - ◆ Output power = 250 W
 - Power gain = 17 dB
 - ◆ Efficiency = 55 %
- Easy power control
- Integrated ESD protection
- High flexibility with respect to pulse formats
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (1.2 GHz to 1.4 GHz)
- Internally matched for ease of use
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC



1.3 Applications

■ L-band power amplifiers for radar applications in the 1.2 GHz to 1.4 GHz frequency range

2. Pinning information

Table 2. Pinning

Table 2.	Filling		
Pin	Description	Simplified outline	Graphic symbol
BLL6H12	14L-250 (SOT502A)		
1	drain		,
2	gate	1	1 <u> </u>
3	source	[1]	2
		2	3 sym112
DI I OLIVO	4.41.0.050 (OOT500D)		Sylli 12
BLL6H12	14LS-250 (SOT502B)		
1	drain		
2	gate		1
3	source	[1]	2
		2	3
			sym112

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BLL6H1214L-250	-	flanged LDMOST ceramic package; 2 mounting holes; 2 leads	SOT502A			
BLL6H1214LS-250	-	earless flanged LDMOST ceramic package; 2 leads	SOT502B			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	100	V
V_{GS}	gate-source voltage		-0.5	+13	V
I_D	drain current		-	42	Α
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		-	200	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
Z _{th(j-c)} transient thermal impedance from junction to case	•	T_{case} = 85 °C; P_L = 250 W		
	junction to case	t_p = 100 μ s; δ = 10 %	0.10	K/W
	t_p = 200 μ s; δ = 10 %	0.13	K/W	
		t_p = 300 μ s; δ = 10 %	0.15	K/W
		t_p = 100 μ s; δ = 20 %	0.14	K/W
		t_p = 500 μ s; δ = 20 %	0.20	K/W

6. Characteristics

Table 6. DC characteristics

 $T_i = 25 \,^{\circ}\text{C}$.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 2.7 \text{ mA}$	100	-	-	V
V _{GS(th)}	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 270 \text{ mA}$	1.3	1.8	2.25	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V}$	-	-	1.4	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	32	42	-	Α
I_{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	140	nΑ
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_{D} = 270 \text{ mA}$	1.6	2.3	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 9.5 \text{ A}$	-	100	169	mΩ

Table 7. RF characteristics

Mode of operation: pulsed RF; t_p = 300 μ s; δ = 10 %; RF performance at V_{DS} = 50 V; I_{Dq} = 100 mA; T_{case} = 25 °C; unless otherwise specified, in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
P_L	output power		250	-	-	W
V_{DS}	drain-source voltage	$P_{L} = 250 \text{ W}$	-	-	50	V
G_p	power gain	$P_{L} = 250 \text{ W}$	15	17	-	dB
t_p	pulse duration	$P_{L} = 250 \text{ W}$	-	300	500	μS
δ	duty cycle	$P_{L} = 250 \text{ W}$	-	10	20	%
RL_{in}	input return loss	$P_{L} = 250 \text{ W}$	-	10	-	dB
P _{L(1dB)}	output power at 1 dB gain compression		-	300	-	W
η_{D}	drain efficiency	$P_{L} = 250 \text{ W}$	49	55	-	%
$P_{droop(pulse)}$	pulse droop power	$P_{L} = 250 \text{ W}$	-	0	0.3	dB
t _r	rise time	$P_{L} = 250 \text{ W}$	-	15	-	ns
t _f	fall time	$P_L = 250 \text{ W}$	-	5	-	ns

6.1 Ruggedness in class-AB operation

The BLL6H1214L-250 and BLL6H1214LS-250 are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 50 V; I_{Dq} = 100 mA; P_L = 250 W; t_p = 300 μ s; δ = 10 %.

7. Application information

7.1 Impedance information

Table 8. Typical impedance *Typical values unless otherwise specified.*

f	Z _S	Z_L
GHz	Ω	Ω
1.2	1.268 – j2.623	2.987 - j1.664
1.3	2.193 – j2.457	2.162 – j1.326
1.4	2.359 - i2.052	1.604 – i1.887

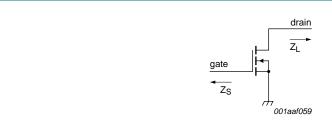
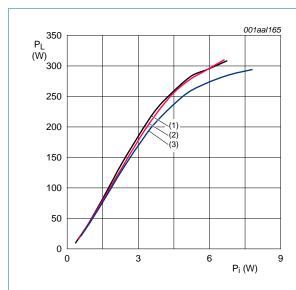


Fig 1. Definition of transistor impedance

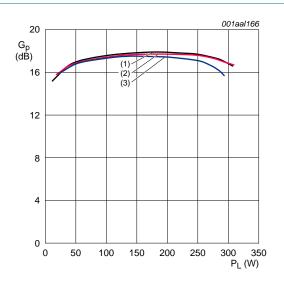
7.2 RF performance



 V_{DS} = 50 V; t_p = 300 μ s; δ = 10 %; I_{Dq} = 100 mA.

- (1) f = 1200 MHz
- (2) f = 1300 MHz
- (3) f = 1400 MHz

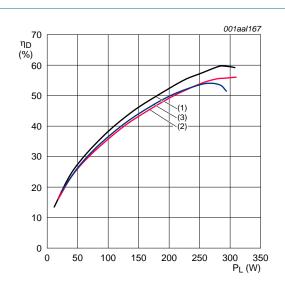
Fig 2. Output power as a function of input power; typical values



 $V_{DS} = 50 \text{ V}; t_p = 300 \text{ } \mu\text{s}; \delta = 10 \text{ } \%; I_{Dq} = 100 \text{ mA}.$

- (1) f = 1200 MHz
- (2) f = 1300 MHz
- (3) f = 1400 MHz

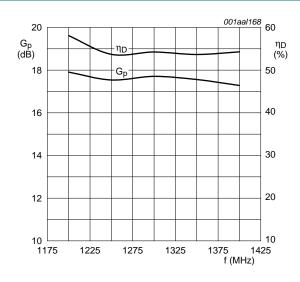
Fig 3. Power gain as a function of load power; typical values



 V_{DS} = 50 V; t_p = 300 $\mu s;~\delta$ = 10 %; I_{Dq} = 100 mA.

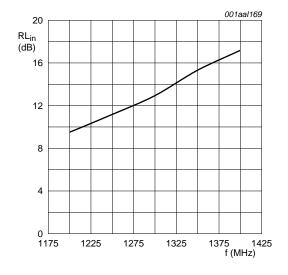
- (1) f = 1200 MHz
- (2) f = 1300 MHz
- (3) f = 1400 MHz

Fig 4. Drain efficiency as a function of load power; typical values



 P_L = 250 W; V_{DS} = 50 V; t_p = 300 $\mu s;~\delta$ = 10 %; I_{Dq} = 100 mA.

Fig 5. Power gain and drain efficiency as function of frequency; typical values



 P_L = 250 W; V_{DS} = 50 V; t_p = 300 μs ; δ = 10 %; I_{Dq} = 100 mA.

Fig 6. Input return loss as a function of frequency; typical value

7.3 Application circuit

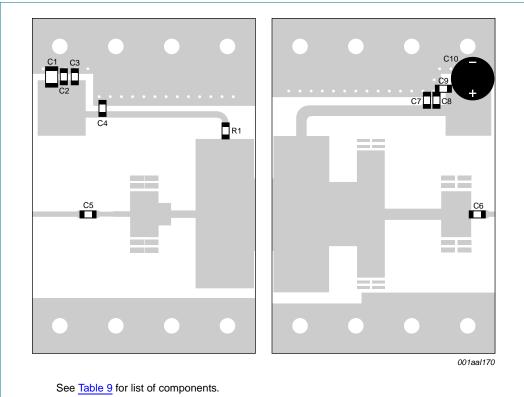


Fig 7. Component layout for class-AB application circuit

Table 9. List of components

See Figure 7.

Striplines are on a Rodgers Duroid 6006 Printed-Circuit Board (PCB); $\varepsilon_r = 6.15$ F/m; thickness = 0.64 mm

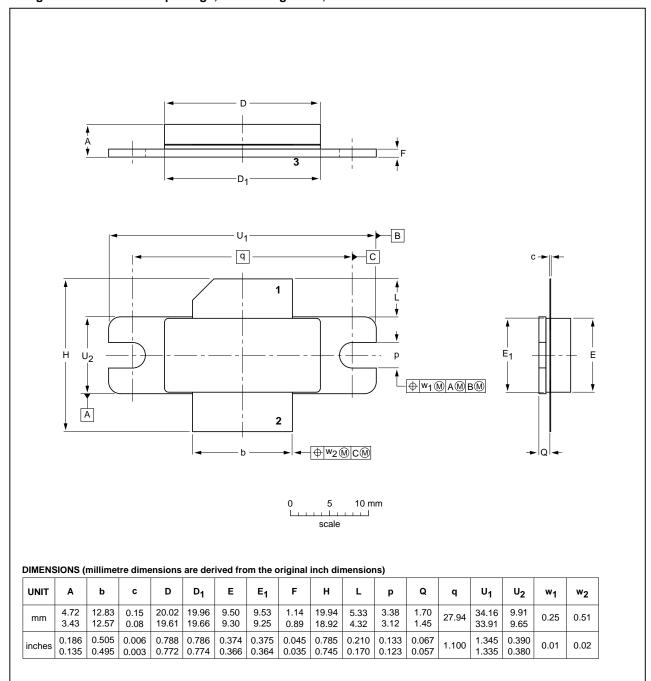
Component	Description	Value	Remarks
C1	multilayer ceramic chip capacitor	10 μF; 35 V	[1]
C2, C4	multilayer ceramic chip capacitor	51 pF	[2]
C3, C8	multilayer ceramic chip capacitor	1 nF	[2]
C5	multilayer ceramic chip capacitor	82 pF	[3]
C6, C7	multilayer ceramic chip capacitor	56 pF	[3]
C9	multilayer ceramic chip capacitor	100 pF	[3]
C10	electrolytic capacitor	47 μF; 63 V	
R1	SMD resistor	10 Ω	0603

- [1] American Technical Ceramics type 100A or capacitor of same quality.
- [2] American Technical Ceramics type 100B or capacitor of same quality.
- [3] American Technical Ceramics type 800B or capacitor of same quality.

8. Package outline

Flanged LDMOST ceramic package; 2 mounting holes; 2 leads

SOT502A



OUTLINE		REFERENCES			EUROPEAN ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT502A						99-12-28 03-01-10	

Fig 8. Package outline SOT502A

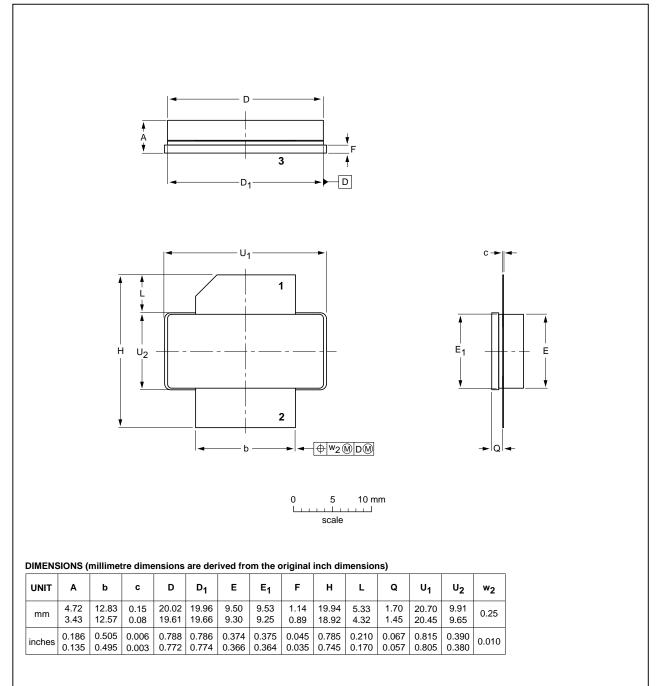
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Earless flanged LDMOST ceramic package; 2 leads

SOT502B



OUTLINE	REFERENCES			EUROPEAN ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT502B						03-01-10- 07-05-09

Fig 9. Package outline SOT502B

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9. Abbreviations

Table 10. Abbreviations

Acronym	Description
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
RF	Radio Frequency
SMD	Surface Mounted Device
VSWR	Voltage Standing-Wave Ratio

10. Revision history

Table 11. Revision history

<u> </u>				
Document ID	Release date	Data sheet status	Change notice	Supersedes
BLL6H1214L-250_1214LS-250 v.3	20100714	Product data sheet	-	BLL6H1214L-250_1214LS-250_2
Modifications:	• Table	7 on page 3: the min	imum value of η_{D} h	nas been changed.
BLL6H1214L-250_1214LS-250_2	20100302	Objective data sheet	-	BLL6H1214L-250_1214LS-250_1
BLL6H1214L-250_1214LS-250_1	20091211	Objective data sheet	-	-

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Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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LDMOS L-band radar power transistor

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13. Contents

1	Product profile
1.1	General description 1
1.2	Features and benefits
1.3	Applications 2
2	Pinning information 2
3	Ordering information
4	Limiting values
5	Thermal characteristics 3
6	Characteristics
6.1	Ruggedness in class-AB operation 4
7	Application information 4
7.1	Impedance information 4
7.2	RF performance 5
7.3	Application circuit
8	Package outline 8
9	Abbreviations
10	Revision history
11	Legal information 11
11.1	Data sheet status
11.2	Definitions
11.3	Disclaimers
11.4	Trademarks12
12	Contact information 12
13	Contents

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